

SUPA

Towards four dimensional particle tracking for biological applications

H. I. Campbell¹, P. A. Dalgarno¹, A. Putoud¹, C. C. Diez¹, A. Baird¹, S. G. Aitken¹, D. P. Towers², C. E. Towers², R. J. Warburton¹ and A. H. Greenawav¹

1School of Engineering and Physical Sciences, Physics Department (part of the Edinburgh Research Partnership), David Brewster Building, Riccarton, Edinburgh, EH14 4AS ² School of Mechanical Engineering, University of Leeds, Leeds, LS2 9JT

We acknowledge funding from STFC and EPSRC.

Email: H.I.Campbell@hw.ac.uk | Web: http://waf.eps.hw.ac.uk Particle Tracking at the Nano-Scale

Background and Experimental Details

optically

orders.

(2006))

efficient. Etch depth

For telecentric

imaging (equal

more

A weak, off-axis Fresnel lens combined with a conventional lens creates an imaging device that delivers simultaneous in-focus images of multiple object depths (see fig. 1).

How does it work?

• Quadratic curvature of the grating rulings imposes a defocus detour phase on any incident wave-front \rightarrow grating acts as a lens with a different focal length in each order.

• For constant image distance (v) the in-focus image in each order corresponds to a different object depth. Object plane separation (Δz) is determined by the curvature of the grating.



Figure 1: Multi-plane imaging with a distorted diffraction grating

A high magnification microscope delivers an image of the sample to an optically accessible plane (iris plane in fig.2). The grating-relay lens combination images multiple object planes either side of the magnified image plane.

Sample: 215 nm diameter holes ("nanoholes") in an metal mask are illuminated from below, creating perfect point sources, simulating fluorescently tagged bioparticles

High precision piezo positioners are used to move the nanoholes in X.Y and Z. This position information allows experimental verification of our particle tracking algorithm.



Figure 2: Schematic of the 4D Particle Tracking System

optical axis (the Z-axis) within a specimen (see fig.3).

Figure 3: A through focal Z-series of a single na

- The centroid of each image is used to find the position in X and Y.
- The particle's position in Z is calculated using an Image Sharpness measurement.

What is Image Sharpness and how is it calculated?

Image Sharpness - measure of image quality, dependent on the degree of aberration (e.g. defocus) in the image, maximised for a focussed image.

Usually captured as a sequential series

Advantage of the grating method :

Simultaneous capture of images on 3 (or

more) planes facilitates rapid Z-series

acquisition to study fast dynamic

processes. Also less likely to "lose" tracked

particles during imaging (if they move away from one measurement plane they will

of images \rightarrow inherent time delay.

appear in another).

The Image Sharpness is the integrated area under the Modulation Transfer Function squared (MTF²) of a given image.

Fig. 4 shows the area under the MTF decreasing as the level of defocus aberration on the wave-front is increased (→ Image Sharpness decreases too).

The Image Sharpness can also be calculated by integrating the square of the original intensity image.

Image Sharpness as a function of particle position - Experimental Results:



Figure 5: Image Sharpness vs. Particle Displacement for a single Z-series (no grating) - gives ambiguous result.

The width, height and shape of the Image Sharpness curve produced by a Z-series depends on the aberrations present in the system (see figs 5 & 6).

• Problem: Fig. 5 shows that for a single Z-series the Image Sharpness gives an ambiguous measure of the particle's Z-position.

• Solution: The grating provides 3 images at each position. Comparing the calculated Image Sharpness for the image in each diffraction order gives an unambiguous Z-position measurement (fig. 6).

Accuracy : We have demonstrated single particle tracking (of a nanohole) through a 50x50x6 µm volume with a repeatability accuracy of better than 50nm in each direction.



Application - Multi-plane imaging facilitates multiple target particle tracking for Particle Imaging Velocimetry.

roscope courtesy

♦ Benefit - Potential 30% saving in fuel consumption in combustion engines through improved fuel mix.

Demonstration - Initial experiments mapping the trajectory of a fluorescent bead provide 3D resolution from a single viewpoint that matches state-of-the-art Figure 8: Mapping the trajectory of a fluorescent bead. accuracy (fig. 8).



• Application - Multi-plane imaging allows fast

capture of Z-series to study dynamic processes

Benefit – Our 3D imaging system is easy to

incorporate into existing systems. It is

unobtrusive, inexpensive and uses well

Demonstration - Our system is added onto a

established imaging techniques.

Future Work

Live Cell Imaging and Beyond!

in vivo.

Particle Tracking:

Fluorescent particle tracking at Brownian motion speeds (potential application to virus tracking and cell dynamics).

Phase Contrast Imaging - Benefits:

Transmitted light technique - useful for imaging whole cells, no addition of potentially damaging contrast agents/dves.

Multi-plane imaging can be used to observe rapid changes in cell shape (e.g. during mitosis).

Demonstration – Fig. 9 shows 3D phase contrast images captured using the system shown in fig. 7, with a 100x phase contrast objective (equipment courtesy of Dr Viki Allan, University of Manchester).



Figure 9: 3D Phase contrast images of a 2µm diameter polymer bead phagocytosed into a Chinese Hamster Ovarian fibroblast cell. a-c bead is brought to focus in the -1, 0 and +1 orders sequentially. (sample courtesy of Dr. Lynn Paterson, Heriot-Watt University),

Extension to Wave-front Sensing - Benefits:

- Only requires further analysis of the data, not additional equipment.
- Would provide information about system and specimen-induced aberrations.
- Characterisation and subsequent rejection of non-defocus aberrations will increase the accuracy of the Z-position measurement.





Diffraction Order -1 0 +1

Particle Displacement (um)

Figure 6: Image Sharpness vs. Particle Displacement tracking a single nanohole on 3 planes with the grating